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L Number	Hits	Search Text	DB	Time stamp
1	2066	linear adj address	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/13 22:34
2	289	segment adj descriptor near4 table	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/13 22:35
3	162	segment adj descriptor adj table	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/13 22:35
4	67	(linear adj address) and (segment adj descriptor adj table)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/13 22:36
5	457	segment adj selector	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/13 22:36
6	59	(segment adj descriptor adj table) and (segment adj selector)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/13 22:36
7	19	((segment adj descriptor adj table) and (segment adj selector)) and (fail or failure or corrupt)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/13 22:37
8	171	global near3 descriptor near3 table	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/13 22:37
9	148	local near3 descriptor near3 table	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/13 22:37
10	103	(global near3 descriptor near3 table) and (local near3 descriptor near3 table)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/13 22:38
11	404	(segment adj selector) and (first or second)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/13 22:38
12	53	(segment adj selector) near4 (first or second)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/13 22:39
13	8	(linear adj address) and (segment adj selector) and (global near3 descriptor near3 table) and (local near3 descriptor near3 table) and ((segment adj selector) near4 (first or second))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/13 22:40
14	2727323	examin$4 or check$4 or propert$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/13 22:40

15	6	((linear adj address) and (segment adj selector) and (global near3 descriptor near3 table) and (local near3 descriptor near3 table) and ((segment adj selector) near4 (first or second))) and (examin$4 or check$4 or propert$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/13 22:41
16	6	(((linear adj address) and (segment adj selector) and (global near3 descriptor near3 table) and (local near3 descriptor near3 table) and ((segment adj selector) near4 (first or second))) and (examin$4 or check$4 or propert$4)) and register	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/13 22:41

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```
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